

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/565,233	CROTEAU ET AL.	
Examiner	Art Unit	
Yong D. Pak	1652	

	SEARCHED						
Class	Subclass	Date	Examiner				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
435	189	2/25/2008	YP		
536	23.2	2/25/2008	YP		
435	440	2/25/2008	YP		
stic: seq id no:1 and 2		2/25/2008	ΥP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
stic: seq id no:1 and 2, see SCORE	2/25/2008	ΥP		
EAST (all databases): inventor and text search, see search history	2/25/2008	ΥP		
stn (medline, caplus, biosis, agricola): text search, see search history	2/26/2008	ΥP		
PALM: inventor search	2/25/2008	ΥP		